



제 30회 한국반도체학술대회

The 30th Korean Conference on Semiconductors

2023년 2월 13일(월) ~ 15일(수) | 강원도 하이원리조트(그랜드호텔 컨벤션타워)

2023년 2월 15일(수), 16:00-17:45

Room G (스페이드 II+III, 6층)

K. Memory (Design & Process Technology) 분과 [WG3-K] DRAM, MRAM, and NAND Flash Memory

좌장: 오정훈 마스터(삼성전자), 김성준 교수(동국대학교)

WG3-K-1 16:00-16:30 [초청]	3D NAND Flash Development Status and Challenges Daewoong Kang <i>Seoul National University</i>
WG3-K-2 16:30-17:00 [초청]	Technology of Cross-point MRAM for High Density Memory 김수길, 서수만, 윤종민, 김세연, 나명희 <i>SK Hynix</i>
WG3-K-3 17:00-17:15	Investigation of Dynamic Negative bias Temperature Instability of 1x-nm DRAM Peripheral PMOS Transistors for Cryogenic Memory Applications Ha Young Bang ¹ , Hee Jun Lee ¹ , Jingyu Park ¹ , Jisook Hong ² , Seonhaeng Lee ² , and Dae Hwan Kim ¹ ¹ <i>School of Electrical Engineering, Kookmin University, </i> ² <i>Memory Division, Samsung Electronics Co., Ltd.</i>
WG3-K-4 17:15-17:30	Random Telegraph Noise-Based Analysis of Electron Traps in the Cryogenic Operation of Sub 30-nm DRAM Cell Array Transistors Sangwon Lee ¹ , Ga Won Yang ¹ , Sungju Choi ¹ , Jisook Hong ² , Seonhaeng Lee ² , and Dae Hwan Kim ¹ ¹ <i>School of Electrical Engineering, Kookmin University, </i> ² <i>Memory Division, Samsung Electronics Co., Ltd.</i>
WG3-K-5 17:30-17:45	Analysis of Mechanical Stress on Charge Trap Nitride (CTN) for Program Operation in 3D NAND Flash Memory Donghyun Kim, Kihoon Nam, Chanyang Park, Giho Yang, Jinsu Jeong, Sanguk Lee, Jaewan Lim, and Rock-Hyun Baek <i>Department of Electrical Engineering, POSTECH</i>